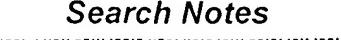


<b>Search Notes</b> 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/721,908	TAKEUCHI ET AL.
	Examiner Huan H. Tran	Art Unit 2861

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner